

Apparatus and method for calibration of an optoelectronic sensor and for mensuration of features on a substrate

Abstract

The invention is based on an apparatus and a method for calibration of an optoelectronic sensor (3) that at least intermittently also receives UV light. A first response characteristic of the sensor (3) is ascertained by illuminating the sensor (3) with the light of a light source (1, 1a, 1b), varying the light quantity of the light incident onto the sensor (3), determining the magnitude of the electrical output signal of the sensor (3) as a function of the light quantity received by the sensor (3).